

Search Notes

Application/Control No.

10/574,933

Examiner

Tuan Quach

Applicant(s)/Patent under
Reexamination

NAKAYAMA ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
257	734, 765, 768-771	3/4/2007	TQ
438	656, 660	3/4/2007	TQ
438	686	3/4/2007	TQ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (USPAT; USPGPUB; EPO; JPO; DERWENT; IBMTDB) see search history printout	3/4/2007	TQ